

Single-Channel: 6N138, 6N139 Dual-Channel: HCPL2730, HCPL2731 Low Input Current High Gain Split Darlington Optocouplers

Features

- Low current – 0.5mA
- Superior CTR-2000%
- Superior CMR-10kV/μs
- CTR guaranteed 0–70°C
- U.L. recognized (File # E90700)
- VDE recognized (File # 120915) Ordering option V, e.g., 6N138V
- Dual Channel – HCPL2730, HCPL2731

Applications

- Digital logic ground isolation
- Telephone ring detector
- EIA-RS-232C line receiver
- High common mode noise line receiver
- μP bus isolation
- Current loop receiver

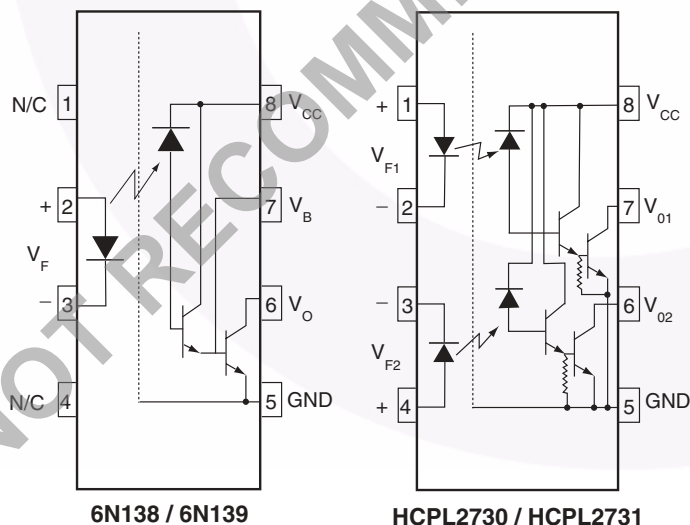
Description

The 6N138/9 and HCPL2730/HCPL2731 optocouplers consist of an AlGaAs LED optically coupled to a high gain split darlington photodetector.

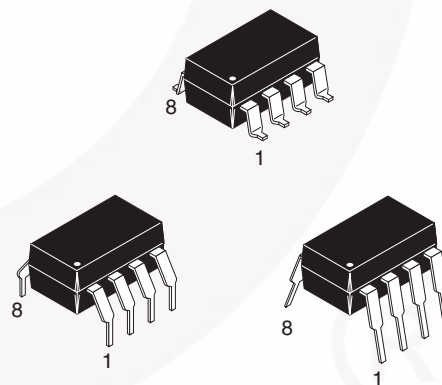
The split darlington configuration separating the input photodiode and the first stage gain from the output transistor permits lower output saturation voltage and higher speed operation than possible with conventional darlington phototransistor optocoupler. In the dual channel devices, HCPL2730/HCPL2731, an integrated emitter-base resistor provides superior stability over temperature.

The combination of a very low input current of 0.5mA and a high current transfer ratio of 2000% makes this family particularly useful for input interface to MOS, CMOS, LSTTL and EIA RS232C, while output compatibility is ensured to CMOS as well as high fan-out TTL requirements. An internal noise shield provides exceptional common mode rejection of 10 kV/μs.

Schematic



Package Outlines



Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter		Value	Units
T _{STG}	Storage Temperature		-55 to +125	°C
T _{OPR}	Operating Temperature		-40 to +85	°C
T _{SOL}	Lead Solder Temperature (Wave solder only. See recommended reflow profile graph for SMD mounting)		260 for 10 sec	°C
EMITTER				
I _F (avg)	DC/Average Forward Input Current	Each Channel	20	mA
I _F (pk)	Peak Forward Input Current (50% duty cycle, 1 ms P.W.)	Each Channel	40	mA
I _F (trans)	Peak Transient Input Current - (≤1μs P.W., 300 pps)		1.0	A
V _R	Reverse Input Voltage	Each Channel	5	V
P _D	Input Power Dissipation	Each Channel	35	mW
DETECTOR				
I _O (avg)	Average Output Current	Each Channel	60	mA
V _{ER}	Emitter-Base Reverse Voltage	6N138 and 6N139	0.5	V
V _{CC} , V _O	Supply Voltage, Output Voltage	6N138, HCPL2730	-0.5 to 7	V
		6N139, HCPL2731	-0.5 to 18	
P _O	Output Power Dissipation	Each Channel	100	mW

Electrical Characteristics ($T_A = 0$ to 70°C unless otherwise specified)**Individual Component Characteristics**

Symbol	Parameter	Test Conditions	Device	Min.	Typ.*	Max.	Unit
EMITTER							
V_F	Input Forward Voltage	$T_A = 25^\circ\text{C}$ Each channel ($I_F = 1.6\text{mA}$)	All		1.30	1.7 1.75	V
BV_R	Input Reverse Breakdown Voltage	$T_A = 25^\circ\text{C}$, $I_R = 10\mu\text{A}$	All	5.0	20		V
$\Delta V_F / \Delta T_A$	Temperature Coefficient of Forward Voltage	$I_F = 1.6\text{mA}$	All		-1.8		mV/ $^\circ\text{C}$
DETECTOR							
I_{OH}	Logic HIGH Output Current	$I_F = 0\text{mA}$, $V_O = V_{CC} = 18\text{V}$ Each Channel	6N139 HCPL2731		0.01	100	μA
		$I_F = 0\text{mA}$, $V_O = V_{CC} = 7\text{V}$ Each Channel	6N138 HCPL2730		0.01	250	
I_{CCL}	Logic LOW supply	$I_F = 1.6\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 18\text{V}$ $I_{F1} = I_{F2} = 1.6\text{mA}$, $V_{CC} = 18\text{V}$ $V_{O1} - V_{O2} = \text{Open}$, $V_{CC} = 7\text{V}$	6N138, 6N139 HCPL2731 HCPL2730		0.4 1.3	1.5 3	mA
I_{CCH}	Logic HIGH Supply	$I_F = 0\text{mA}$, $V_O = \text{Open}$, $V_{CC} = 18\text{V}$ $I_{F1} = I_{F2} = 0\text{mA}$, $V_{CC} = 18\text{V}$ $V_{O1} - V_{O2} = \text{Open}$, $V_{CC} = 7\text{V}$	6N138, 6N139 HCPL2731 HCPL2730		0.05 0.10	10 20	μA

Transfer Characteristics

Symbol	Parameter	Test Conditions	Device	Min.	Typ.*	Max.	Unit
COUPLED							
CTR	Current Transfer Ratio ⁽¹⁾⁽²⁾	$I_F = 0.5\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139 HCPL2731	400	1100 3500		%
		$I_F = 1.6\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139 HCPL2731	500	1300 2500		
		$I_F = 1.6\text{mA}$, $V_O = 0.4\text{V}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N138 HCPL2730	300	1300 2500		
V_{OL}	Logic LOW Output Voltage ⁽²⁾	$I_F = 0.5\text{mA}$, $I_O = 2\text{mA}$, $V_{CC} = 4.5\text{V}$ $I_F = 1.6\text{mA}$, $I_O = 8\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139 6N139 HCPL2731		0.08 0.01	0.4 0.4	V
		$I_F = 0.5\text{mA}$, $I_O = 15\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139 HCPL2731		0.13	0.4	
		$I_F = 12\text{mA}$, $I_O = 24\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N139 HCPL2731		0.20	0.4	
		$I_F = 1.6\text{mA}$, $I_O = 4.8\text{mA}$, $V_{CC} = 4.5\text{V}$ Each Channel	6N138 HCPL2730		0.10	0.4	

*All Typicals at $T_A = 25^\circ\text{C}$

Electrical Characteristics (Continued) ($T_A = 0$ to 70°C unless otherwise specified)**Switching Characteristics** ($V_{CC} = 5\text{V}$)

Symbol	Parameter	Test Conditions	Device	Min.	Typ.*	Max.	Unit
T_{PHL}	Propagation Delay Time to Logic LOW ⁽²⁾ (Fig. 24)	$R_L = 4.7\Omega$, $I_F = 0.5\text{mA}$	6N139			30	μs
		$T_A = 25^\circ\text{C}$			4	25	
		$R_L = 4.7\Omega$, $I_F = 0.5\text{mA}$	HCPL2731			120	
		Each Channel $T_A = 25^\circ\text{C}$			3	100	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$	6N139			2	
		$T_A = 25^\circ\text{C}$			0.2	1	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$, Each Channel	HCPL2730			3	
		$T_A = 25^\circ\text{C}$	HCPL2731		0.3	2	
		$R_L = 2.2\Omega$, $I_F = 1.6\text{mA}$	6N138			15	
T_{PLH}	Propagation Delay Time to Logic HIGH ⁽²⁾ (Fig. 24)	$R_L = 4.7\Omega$, $I_F = 0.5\text{mA}$	6N139			90	μs
		Each Channel	HCPL2731				
		$R_L = 4.7\Omega$, $I_F = 0.5\text{mA}$, $T_A = 25^\circ\text{C}$	6N139		12	60	
		Each Channel	HCPL2731		22		
		$R_L = 270\Omega$, $I_F = 12\text{mA}$	6N139			10	
		$T_A = 25^\circ\text{C}$			1.3	7	
		$R_L = 270\Omega$, $I_F = 12\text{mA}$, Each Channel	HCPL2730			15	
		$T_A = 25^\circ\text{C}$	HCPL2731		5	10	
		$R_L = 2.2\Omega$, $I_F = 1.6\text{mA}$	6N138			50	
ICM_H	Common Mode Transient Immunity at Logic HIGH ⁽³⁾ (Fig. 25)	$I_F = 0\text{mA}$, $ V_{CM} = 10V_{P-P}$, $T_A = 25^\circ\text{C}$, $R_L = 2.2\Omega$	6N138 6N139	1,000	10,000		$\text{V}/\mu\text{s}$
		Each Channel	HCPL2730 HCPL2731				
ICM_L	Common Mode Transient Immunity at Logic LOW ⁽³⁾ (Fig. 25)	$(I_F = 1.6\text{mA}, V_{CM} = 10V_{P-P}, R_L = 2.2\Omega)$ $T_A = 25^\circ\text{C}$	6N138 6N139	1,000	10,000		$\text{V}/\mu\text{s}$
		Each Channel	HCPL2730 HCPL2731				

** All Typicals at $T_A = 25^\circ\text{C}$

Electrical Characteristics (Continued) ($T_A = 0$ to 70°C unless otherwise specified)**Isolation Characteristics**

Symbol	Characteristics	Test Conditions	Min.	Typ.*	Max.	Unit
I_{I-O}	Input-Output Insulation Leakage Current ⁽⁴⁾	Relative humidity = 45%, $T_A = 25^\circ\text{C}$, $t = 5\text{s}$, $V_{I-O} = 3000\text{VDC}$			1.0	μA
V_{ISO}	Withstand Insulation Test Voltage ⁽⁴⁾	$RH \leq 50\%$, $T_A = 25^\circ\text{C}$, $I_{I-O} \leq 2\mu\text{A}$, $t = 1\text{ min.}$	2500			V_{RMS}
R_{I-O}	Resistance (Input to Output) ⁽⁴⁾	$V_{I-O} = 500\text{VDC}$		10^{12}		Ω
C_{I-O}	Capacitance (Input to Output) ⁽⁴⁾⁽⁵⁾	$f = 1\text{MHz}$		0.6		pF
I_{I-I}	Input-Input Insulation Leakage Current ⁽⁶⁾	$RH \leq 45\%$, $V_{I-I} = 500\text{VDC}$, $t = 5\text{s}$, HCPL2730/2731 only		0.005		μA
R_{I-I}	Input-Input Resistance ⁽⁶⁾	$V_{I-I} = 500\text{VDC}$, HCPL2730/2731 only		10^{11}		Ω
C_{I-I}	Input-Input Capacitance ⁽⁶⁾	$f = 1\text{MHz}$, HCPL2730/2731 only		0.03		pF

*All Typicals at $T_A = 25^\circ\text{C}$ **Notes:**

- Current Transfer Ratio is defined as a ratio of output collector current, I_O , to the forward LED input current, I_F , times 100%.
- Pin 7 open. (6N138 and 6N139 only)
- Common mode transient immunity in logic HIGH level is the maximum tolerable (positive) dV_{cm}/dt on the leading edge of the common mode pulse signal V_{CM} , to assure that the output will remain in a logic HIGH state (i.e., $V_O > 2.0\text{V}$). Common mode transient immunity in logic LOW level is the maximum tolerable (negative) dV_{cm}/dt on the trailing edge of the common mode pulse signal, V_{CM} , to assure that the output will remain in a logic LOW state (i.e., $V_O < 0.8\text{V}$).
- Device is considered a two terminal device: Pins 1, 2, 3 and 4 are shorted together and Pins 5, 6, 7 and 8 are shorted together.
- For dual channel devices, C_{I-O} is measured by shorting pins 1 and 2 or pins 3 and 4 together and pins 5 through 8 shorted together.
- Measured between pins 1 and 2 shorted together, and pins 3 and 4 shorted together.

Electrical Characteristics (Continued) $T_A = 25^\circ\text{C}$ unless otherwise specified)

Current Limiting Resistor Calculations

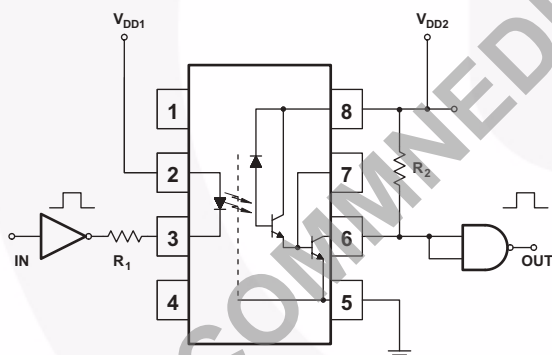
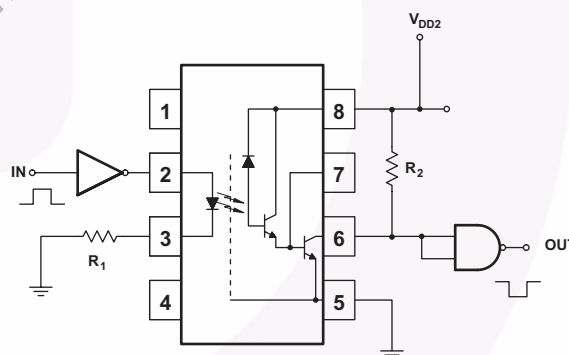
$$R_1 \text{ (Non-Invert)} = \frac{V_{DD1} - V_{DF} - V_{OL1}}{I_F}$$

$$R_1 \text{ (Invert)} = \frac{V_{DD1} - V_{OH1} - V_{DF}}{I_F}$$

$$R_2 = \frac{V_{DD2} - V_{OLX} (@ I_L - I_2)}{I_L}$$

Where: V_{DD1} = Input Supply Voltage V_{DD2} = Output Supply Voltage V_{DF} = Diode Forward Voltage V_{OL1} = Logic "0" Voltage of Driver V_{OH1} = Logic "1" Voltage of Driver I_F = Diode Forward Current V_{OLX} = Saturation Voltage of Output Transistor I_L = Load Current Through Resistor R_2 I_2 = Input Current of Output Gate

INPUT			R1 (V)	OUTPUT						
				CMOS @ 5V	CMOS @ 10V	74XX	74LXX	74SXX	74LSXX	74HXX
				R2 (V)	R2 (V)	R2 (V)	R2 (V)	R2 (V)	R2 (V)	R2 (V)
CMOS @ 5V	NON-INV.	2000	1000	2200	750	1000	1000	1000	560	
	INV.	510								
CMOS @ 10V	NON-INV.	5100								
	INV.	4700								
74XX	NON-INV.	2200								
	INV.	180								
74LXX	NON-INV.	1800								
	INV.	100								
74SXX	NON-INV.	2000								
	INV.	360								
74LSXX	NON-INV.	2000								
	INV.	180								
74HXX	NON-INV.	2000								
	INV.	180								

Fig. 1 Resistor Values for Logic Interface**Fig. 2 Non-Inverting Logic Interface****Fig. 3 Inverting Logic Interface**

Typical Performance Curves

Fig. 4 LED Forward Current vs. Forward Voltage

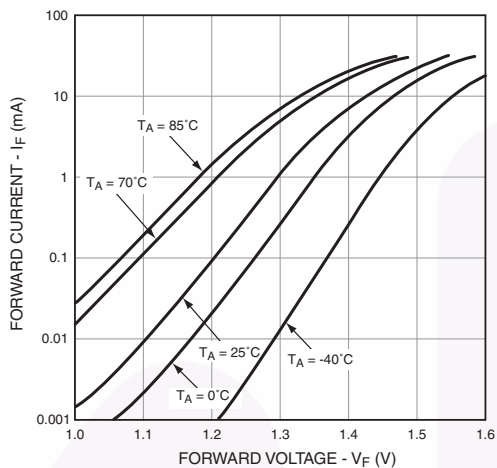


Fig. 5 LED Forward Voltage vs. Temperature

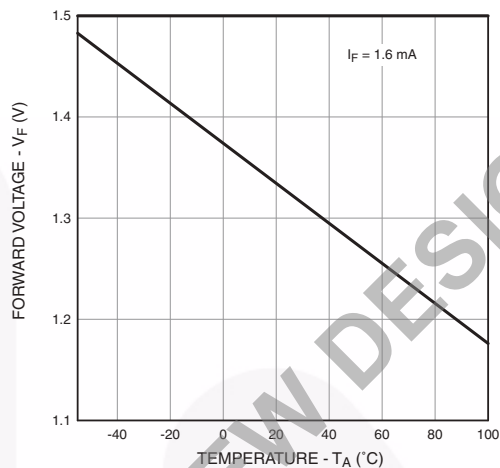


Fig. 6 Non-saturated Rise and Fall Times vs. Load Resistance (6N138 / 6N139 Only)

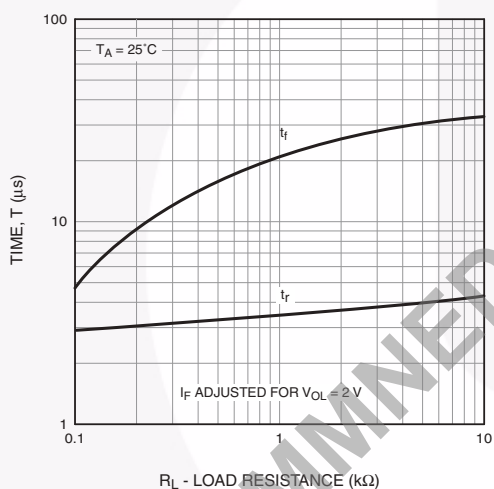


Fig. 7 Non-saturated Rise and Fall Times vs. Load Resistance (HCPL2730 / HCPL2731 Only)

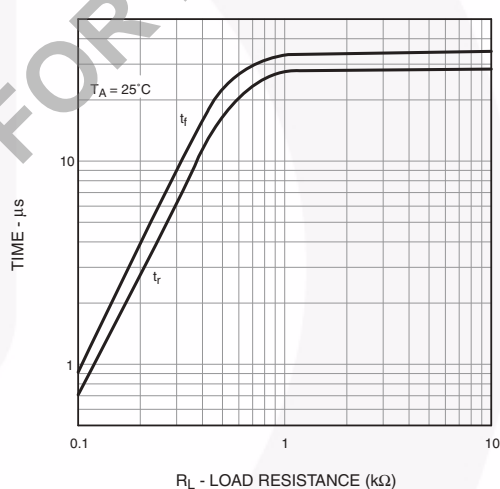


Fig. 8 Propagation Delay To Logic Low vs. Base-Emitter Resistance (HCPL2730 / HCPL2731 Only)

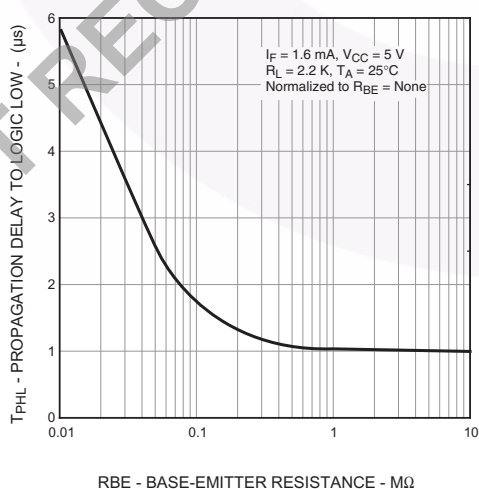
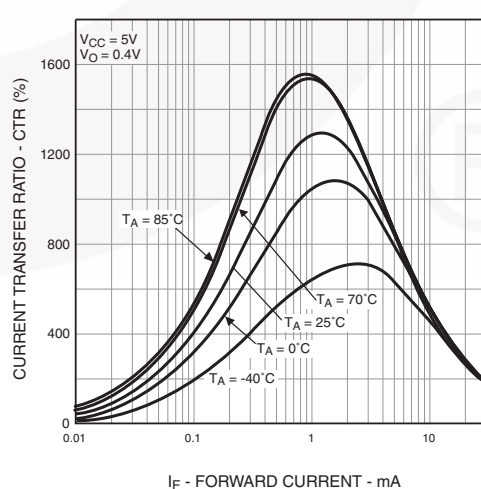


Fig. 9 Current Transfer Ratio vs. Forward Current (6N138 / 6N139 Only)



Typical Performance Curves (Continued)

Fig. 10 Current Transfer Ratio vs. Base-Emitter Resistance
(6N138 / 6N139 Only)

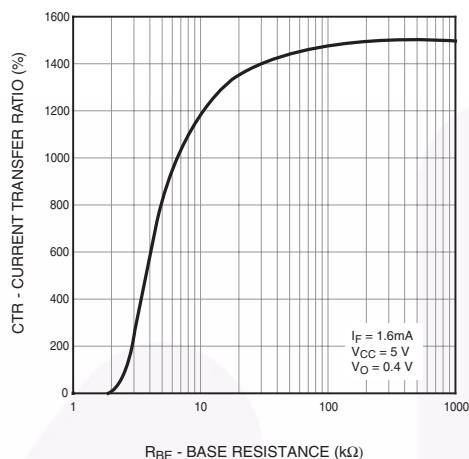


Fig. 11 Current Transfer Ratio vs. Forward Current
(HCPL2730 / HCPL2731 Only)

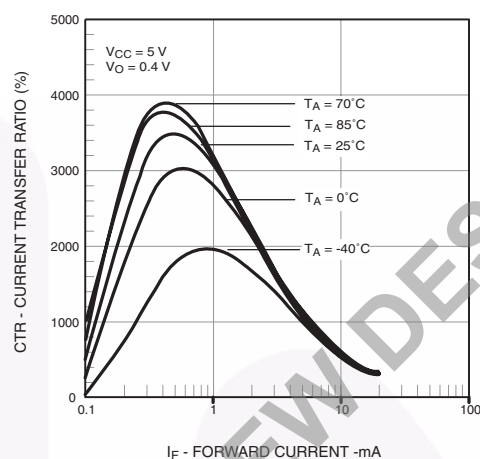


Fig. 12 Output Current vs Output Voltage
(6N138 / 6N139 Only)

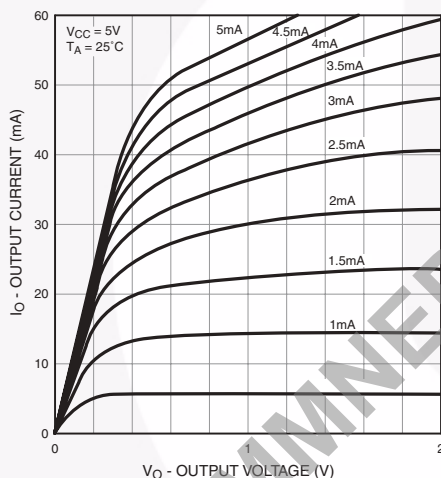


Fig. 13 Output Current vs Output Voltage
(HCPL2730 / HCPL2731 Only)

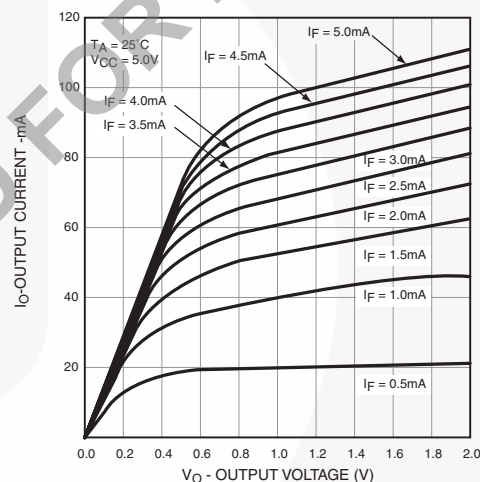


Fig. 14 Output Current vs. Input Diode Forward Current
(6N138 / 6N139 Only)

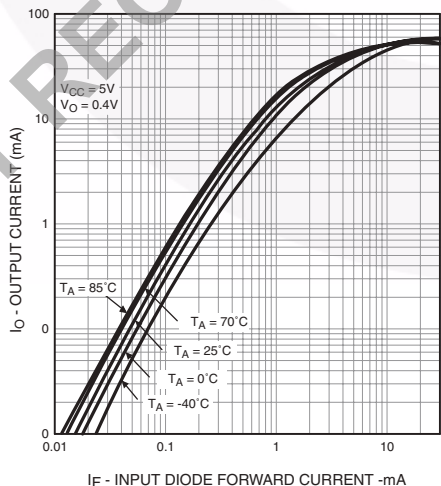
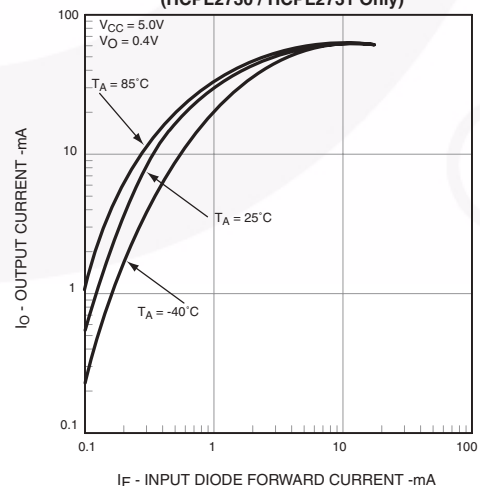


Fig. 15 Output Current vs Input Diode Forward Current
(HCPL2730 / HCPL2731 Only)



Typical Performance Curves (Continued)

Fig. 16 Logic Low Supply Current vs. Input Diode Forward Current (6N138 / 6N139 Only)

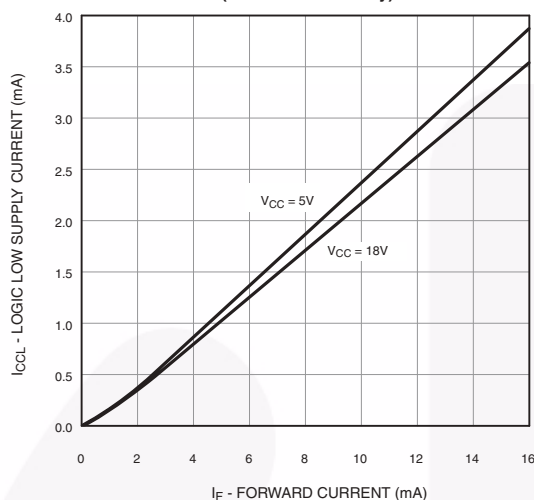


Fig. 17 Logic Low Supply Current vs. Input Diode Forward Current (HCPL2730 / HCPL2731 Only)

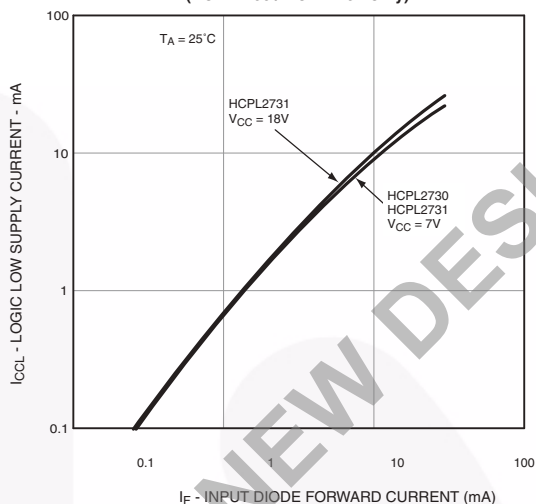


Fig. 18 Propagation Delay vs. Input Diode Forward Current (6N138 / 6N139 Only)

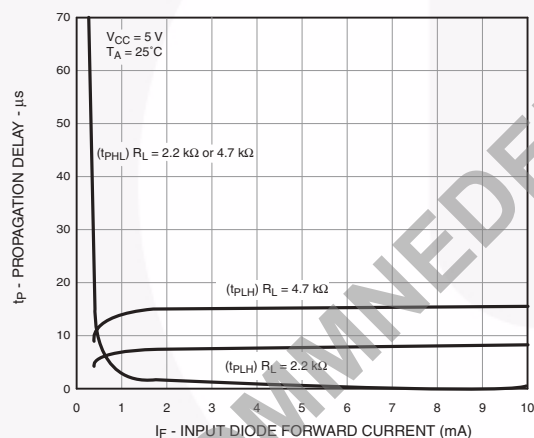


Fig. 19 Propagation Delay vs. Input Diode Forward Current (HCPL2730 / HCPL2731 Only)

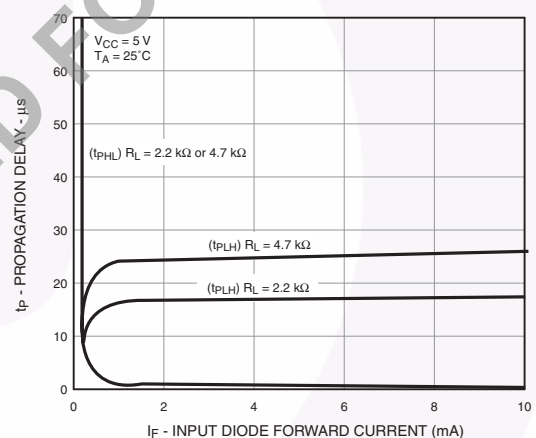


Fig. 20 Propagation Delay to Logic Low vs. Pulse Period (6N138 / 6N139 Only)

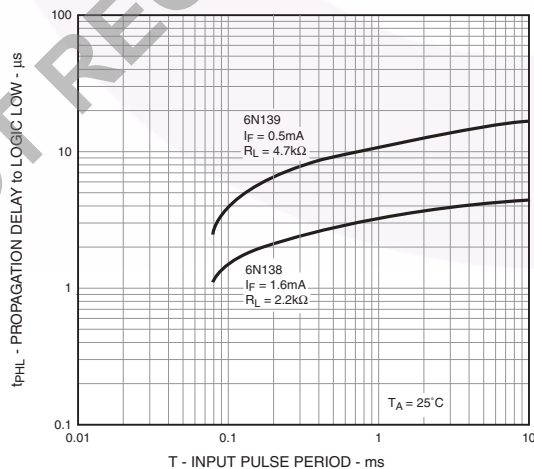
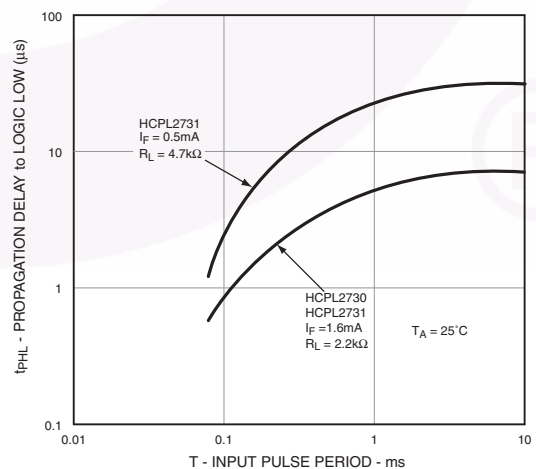
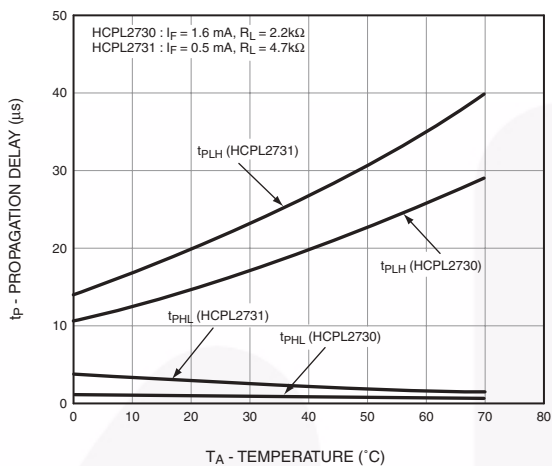
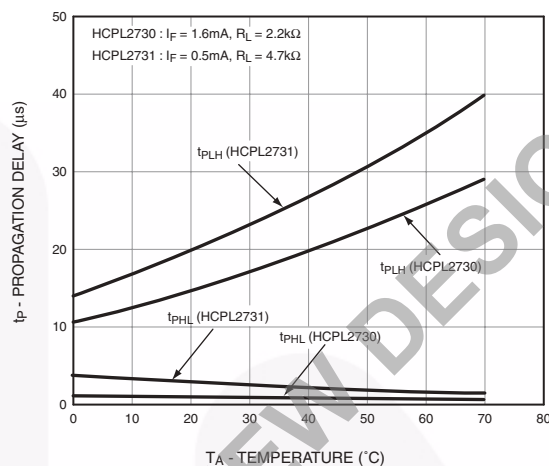


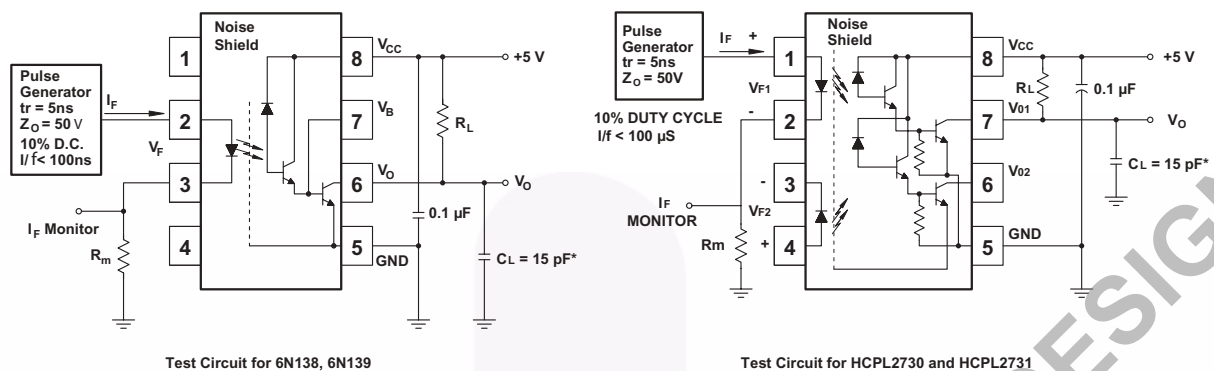
Fig. 21 Propagation Delay to Logic Low vs. Pulse Period (HCPL2730 / HCPL2731 Only)



Typical Performance Curves (Continued)

Fig. 22 Propagation Delay vs. Temperature
(6N138 / 6N139 Only)Fig. 23 Propagation Delay vs. Temperature
(HCPL2730 / HCPL2731 Only)

Test Circuits



Test Circuit for 6N138, 6N139

Test Circuit for HCPL2730 and HCPL2731

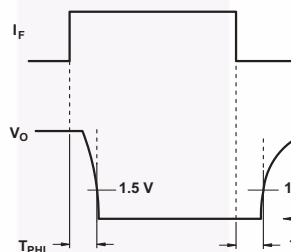
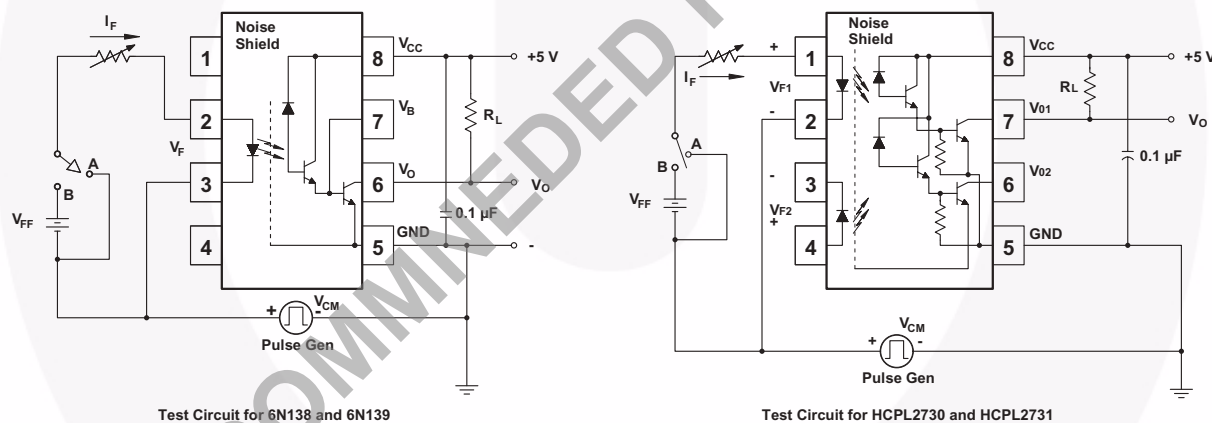


Fig. 24 Switching Time Test Circuit



Test Circuit for 6N138 and 6N139

Test Circuit for HCPL2730 and HCPL2731

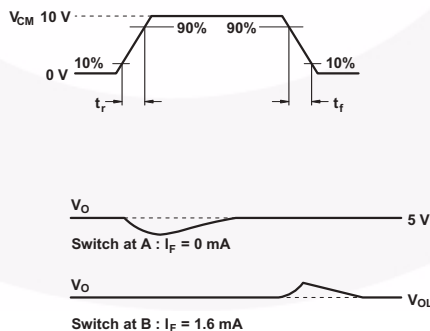
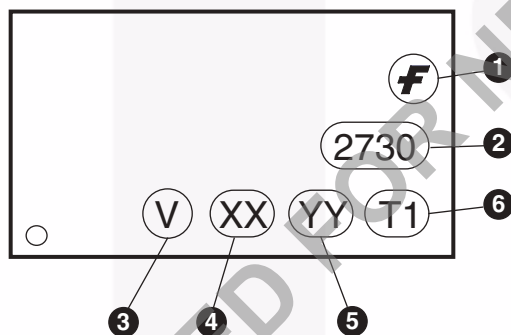


Fig. 25 Common Mode Immunity Test Circuit

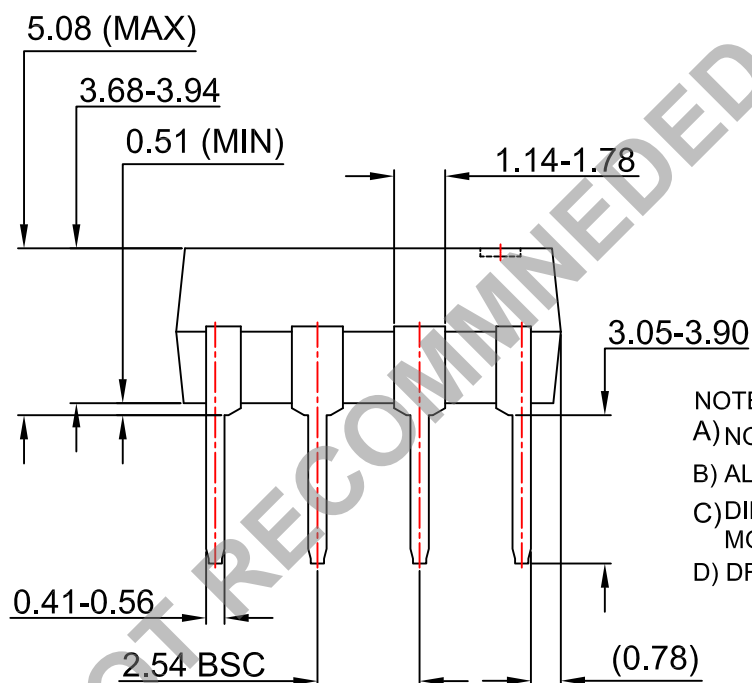
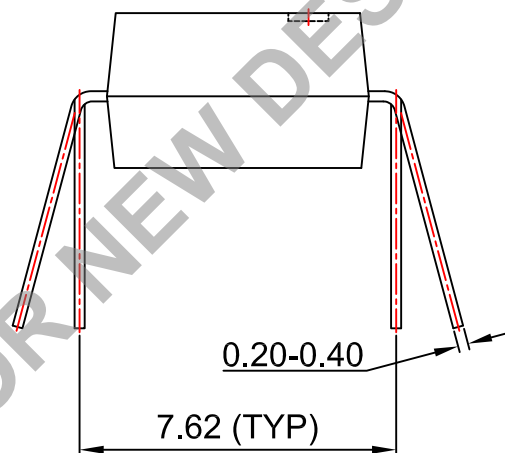
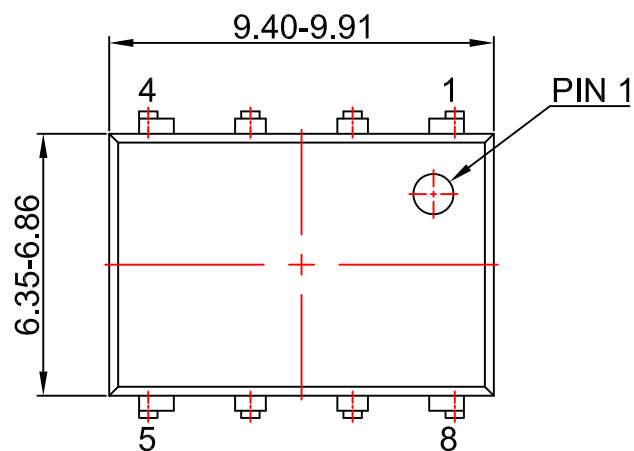
Ordering Information

Option	Example Part Number	Description
No Suffix	6N138	Standard Through Hole Device, 50 pcs per tube
S	6N138S	Surface Mount Lead Bend
SD	6N138SD	Surface Mount; Tape and reel
W	6N138W	0.4" Lead Spacing
V	6N138V	VDE0884
WV	6N138WV	VDE0884; 0.4" lead spacing
SV	6N138SV	VDE0884; surface mount
SDV	6N138SDV	VDE0884; surface mount; tape and reel

Marking Information



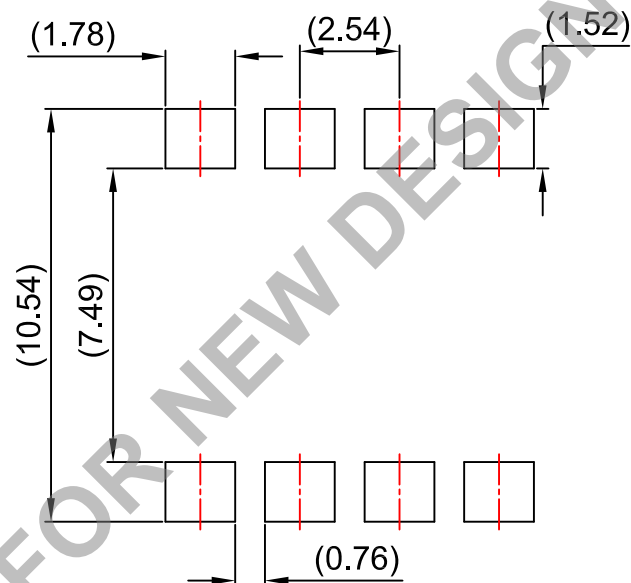
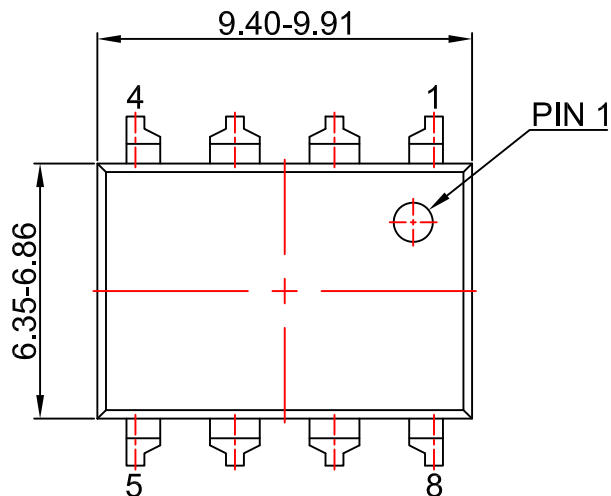
Definitions	
1	Fairchild logo
2	Device number
3	VDE mark (Note: Only appears on parts ordered with VDE option – See order entry table)
4	Two digit year code, e.g., '07'
5	Two digit work week ranging from '01' to '53'
6	Assembly package code



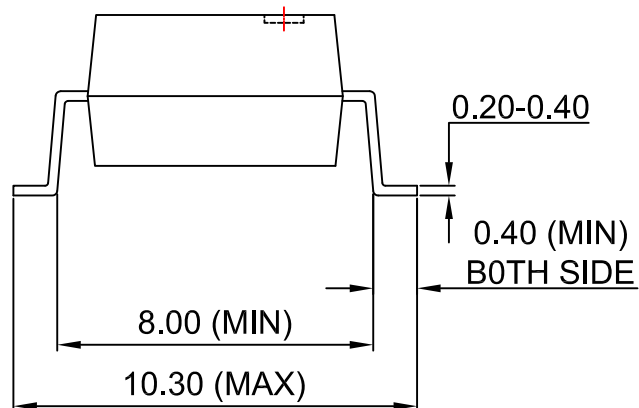
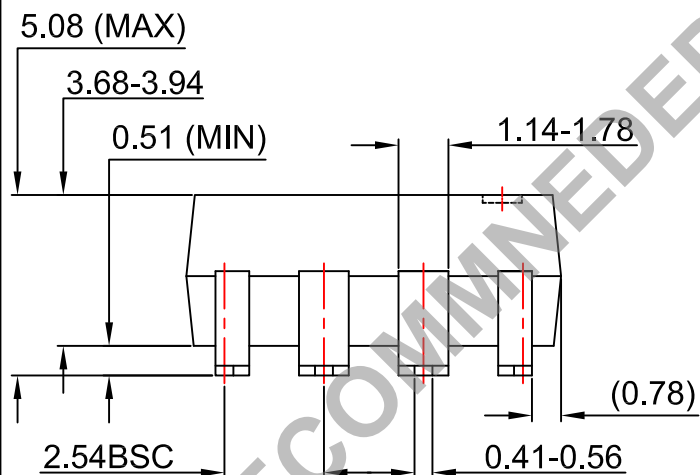
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